Ongoing electronic development in the CERN beam instrumentation group: challenges and solutions for the measurement of particle accelerator beam parameters

Andrea Boccardi on behalf of the Beam Instrumentation group (CERN BE-BI)

What do we measure

- Beam Position
- Beam Loss
- Machine Tune and Chromaticity
- Luminosity
- Transfer line Accelerator Matching

- Beam Intensity — Bunch charge — Total current **Beam Profile** — Transverse Longitudinal

Write once use many times

A common software front end
 Common carrier / specific mezzanine
 The DAB64x (the 1st LHC standard Carrier) is used for several systems

- Beam position monitor
- Beam current transformer
- Abort Gap Monitor
- Luminosity monitor
 - Beam loss monitors
 - Tune system



The VFC (VME FMC Carrier)

2 FMC slots

40 pins on the P2 dedicated to Rear Transition Modules

A configurable low jitter PLL per mezzanine

2x 72Mb SRAM

2Gb DDR3

Programmable clock sources and voltage controlled & temperature compensated oscillators

2 x SFP connected to Gbit capable interfaces

A Spartan6 (150T) fully dedicated to application logic



New Beam Position Monitoring (BPM) System for the Super Proton Synchrotron (SPS)

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- High dynamic range (from 40mVpp up to 580Vpp)
- High resolution required (200uV for ions at the injection) even in single passage mode
- Distributed system: up to 1.5km from the measuring area to the crate area
 - need to put the electronics for the front-ends close to the beam (100krad/10years)
 - qualification of COTS required (240 systems 'only')









New BPM System for the SPS: COTS tests

The components already tested (total dose 100krad):

- None of the tested ADC drivers and LogAmps experienced a noticeable degradation of performances for this dose
 - The FTTX-FT3A05D optical transceiver would be a suitable candidate, unfortunately other tested models are no more an option because of a change in the BW specification
- Al the voltage dividers suffered a shift of the output voltage with the increasing dose, but 2 models seem to be compatible with the application (LT1963-KTT and TPS7A4501KTT)

Components to be tested:

- ADC (any available rad tolerant 14+ bits @ >10 MHz?)
- FPGA (mostly for probability of configuration SRAM corruption)

- Aim: measuring the beam size oscillations in the first turns after the injection
- Measuring technique: OTR screens and imaging system **Requirements:**
 - tens of pixels
 - at least 44KHz acquisition rate









Hamamatsu linear CMOS: 512 pixels 1-50MHz readout











- Several Detector types: ionization chambers, diamond, photo multipliers... — need to cope with currents of different polarities
- 146dB dynamic range : from 200mA (2us) down to 10pA (6ms)
 - use of 2 measuring techniques:
 - 1. direct measure of voltage drop on a shunt (200mA down to 100uA)
 - 2. fully differential frequency converted (improved current to frequency converter) (10mA down to 10pA)
- automatic switch from a measurement technique to the other
 High reliability



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Conclusions

- Due to the high variety of parameters to measure in many different conditions we make an effort to reuse and standardize
- Often our requirements are similar to those of the experiments ... and we are always happy to reuse also electronic modules and ASICs developed in other groups
 - indeed i come here with a shopping list: a 40MHz integrator with no dead time, a rad tolerant 14+bits ADC @40MHz....